

**Problem 1** A random sample  $y_1, \dots, y_n \stackrel{\text{iid}}{\sim} \mathcal{N}(\mu, \sigma^2)$  with average  $\bar{y}$  is to be used to test the null hypothesis  $H_0 : \mu = \mu_0$  against the alternative  $\mu = \mu_1$ ; below  $\sigma^2$  is known and  $z_p = \Phi^{-1}(p)$ .

- (a) Show that if  $\mu_1 > \mu_0$  then the most powerful critical region of size  $\alpha$  is

$$\mathcal{Y}_\alpha^+ = \left\{ y \in \mathbb{R}^n : \bar{y} \geq \mu_0 + \sigma n^{-1/2} z_{1-\alpha} \right\},$$

and find the corresponding most powerful critical region  $\mathcal{Y}_\alpha^-$  when  $\mu_1 < \mu_0$ .

- (b) Are  $\mathcal{Y}_\alpha^+$  and  $\mathcal{Y}_\alpha^-$  uniformly most powerful against their respective alternatives? Explain.  
 (c) Now consider the two-sided alternative  $H : \mu_1 \neq \mu_0$ . Compute the size of the critical region

$$\mathcal{Y}_\beta = \left\{ y \in \mathbb{R}^n : n^{1/2} |\bar{y} - \mu_0| / \sigma \geq z_{1-\beta} \right\}$$

and hence give a two-sided critical region of size  $\alpha$ . Is this uniformly most powerful against  $H$ ?

**Problem 2** Consider the order statistics  $0 < Y_{(1)} < \dots < Y_{(n)}$  of a random sample  $Y_1, \dots, Y_n \stackrel{\text{iid}}{\sim} \exp(\lambda)$ .

- (a) Show that  $\min(Y_1, \dots, Y_r) \sim \exp(r\lambda)$ , and that each  $Y_j$  has the lack-of-memory property

$$P(Y - x > y \mid Y > x) = P(Y > y), \quad x, y > 0.$$

- (b) Show that  $Y_j \stackrel{D}{=} E_j / \lambda$  with  $E_1, \dots, E_n \stackrel{\text{iid}}{\sim} \exp(1)$ , and hence obtain the *Renyi representation*

$$Y_{(r)} \stackrel{D}{=} \frac{1}{\lambda} \sum_{j=1}^r \frac{E_j}{n+1-j}, \quad r = 1, \dots, n.$$

- (c) Find the means and covariances of  $Y_{(1)}, \dots, Y_{(n)}$ .

**Problem 3** Below we consider different ways to combine evidence from independent P-values  $P_1, \dots, P_n$  from testing the same null hypothesis.

- (a) Find the distributions of  $-\log P_j$  and hence of  $S_F = -\sum_j \log P_j$  (Fisher's statistic) and  $S_P = -\sum_j \log(1 - P_j)$  (Pearson's statistic). Give the size  $\alpha$  critical regions for tests based on  $S_F$  and  $S_P$ .  
 (b) Give the size  $\alpha$  critical region for a test based on  $S_T = \min_j P_j$  (Tippett's statistic).  
 (c) Suppose that the alternative is such that  $P(P \leq x) = x^{1/\gamma}$  for  $x \in (0, 1)$  and some  $\gamma > 1$ . Which of  $S_F$ ,  $S_P$  and  $S_T$  is preferable, and why?  
 (d) If  $P$  has density  $x^{a-1}(1-x)^{b-1}/B(a, b)$ , where  $0 < x < 1$ ,  $0 < a < 1$ ,  $b \geq 1$  and  $a \neq b$ , show that the uniformly most powerful test involves  $wS_F + (1-w)S_P$ , where  $w = (1-a)/(b-a)$ .  
 (e) What would you do if it is believed that the null hypothesis holds in a proportion  $1-q$  of the tests and the alternative in (c) holds in the remaining ones, with both  $q$  and  $\gamma$  unknown?